


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/782,960	SEKI, KEMPEI	
	Examiner	Art Unit	
	Hien X. Vo	2863	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
702		75			702	125			
INTERNATIONAL CLASSIFICATION					324	76.21	76.55	76.74	
G	0	1	R	23/00	361	78			
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Hien Vo 06/12/05 (Assistant Examiner) (Date)		John Barlow Supervisory Patent Examiner Technology Center 2800 (Primary Examiner) (Date) 6/22/05		Total Claims Allowed: 4	
<i>Thina Stephens</i> (Legal Instruments Examiner) (Date) 6-27-05				O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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